

10/566686

Express Mail Mailing Label No. EV 630986212 US

PATENT

Attorney Docket No. MIT-166
IAP2010566686 31 JAN 2006

Particulars of prior application:

International Serial No.: PCT/US2004/024747

International Filing Date: July 29, 2004

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

APPLICANT(S): *Liu et al.*

SERIAL NO.: Not yet assigned GROUP NO.: Not yet assigned

FILING DATE: Herewith EXAMINER: Not yet assigned

TITLE: METHOD AND STRUCTURE OF STRAIN CONTROL OF SIGE
BASED PHOTODETECTORS AND MODULATORS

Mail Stop PCT
Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

INFORMATION DISCLOSURE STATEMENT

Sir:

In accordance with the provisions of 37 C.F.R. 1.97 and 1.98, Applicants hereby make of record the patents and publications listed on the accompanying Form PTO-1449, and other information contained herein, for consideration by the Examiner in connection with the examination of the above-identified patent application. In accordance with the U.S. Patent Office's partial waiver of the requirement under 37 C.F.R. 1.98(a)(2)(i), only copies of the foreign patents and non-patent publications are enclosed.

REMARKS

In accordance with the provisions of 37 C.F.R. 1.97, this statement is being filed (CHECK ONE):

(1) within three (3) months of the **filling date** of a national application other than a continued prosecution application under 37 C.F.R. 1.53(d), or within three (3) months of the **date of entry of the national stage** as set forth in 37 C.F.R. 1.491 in an international application, or before the mailing of the **first Office action** on the merits, or before the mailing of a **first Office action** after the filing of a request for continued examination under 37 C.F.R. 1.114; or

(2) after the period defined in (1) but before the mailing date of a **final action** or a **notice of allowance** under 37 C.F.R. 1.311, and

the requisite Statement is below, OR

IAP20 Rec'd FCB/PTO 31 JAN 2006

- the requisite fee under 37 C.F.R. 1.17(p), namely **\$180.00**, is included herein, or
- (3) after the mailing date of a **final action or notice of allowance** but before the payment of the **issue fee**, **AND**
- the requisite Statement is below, **AND**
- the requisite petition fee under 37 C.F.R. 1.17(p), namely **\$180.00** is included herein.

It is respectfully requested that each of the patents and publications listed on the attached Form PTO-1449, and other information contained herein, be made of record in this application.

STATEMENT

As required under 37 C.F.R. 1.97(e), Applicant(s), through the undersigned, hereby state either that:

- 1. Each item of information contained in the Information Disclosure Statement was first cited in any communication from a foreign patent office in a counterpart foreign application **not more than three months** prior to the filing of the Information Disclosure Statement; or
- 2. No item of information contained in the Information Disclosure Statement was cited in a communication from a foreign patent office in a counterpart foreign application, and, to the knowledge of the person signing this Statement after making reasonable inquiry, no item of information contained in the Information Disclosure Statement was known to **any individual** designated in 37 C.F.R. 1.56(c) **more than three months** prior to the filing of the Information Disclosure Statement.

Respectfully submitted,

Date: Jan. 31, 2006
Reg. No. 44,381



Natasha C. Us
Attorney for Applicant(s)
Goodwin Procter LLP
Exchange Place
Boston, Massachusetts 02109
Customer No. 051414

Tel. No.: (617) 570-1806
Fax No.: (617) 523-1231
VER 12/00

10/56688 EXPRESS MAIL MAILING LABEL

NO. EV630986212VS

IAP20 Rec'd PCT/PTO 31 JAN 2006 SHEET 1 OF 1

FORM PTO - 1449		ATTORNEY DOCKET NO.: MIT-166					
INFORMATION DISCLOSURE STATEMENT		APPLICANT(S): Liu <i>et al.</i>					
		SERIAL NO.: Not Yet Assigned					
		FILING DATE: Herewith					
		GROUP: Not Yet Assigned					

U.S. PATENT DOCUMENTS

EXAM. INIT.		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE

FOREIGN PATENT DOCUMENTS

EXAM. INIT.		DOCUMENT NUMBER	DATE	COUNTRY CODE	CLASS	SUB CLASS	FILING DATE	ABSTRACT ONLY	ENGLISH LANG (Y/N)
	B1	WO 03/105189	12/18/2003	WO					
	B2	WO 04/001857	12/31/2003	WO					

OTHER DOCUMENTS: (Including Author, Title, Date, Relevant Pages, Place of Publication)

	C1	Boyanov, et al., "Growth of epitaxial CoSi2 on SiGe (001)", <u>Journal of Applied Physics</u> , American Institute of Physics. New York, US. 86(3):1355-1362 (1999).
	C2	Buchal et al., "Ultrafast Si-based MSM mesa photodetectors with optical waveguide connection," <u>Materials Science in Semiconductor Processing</u> , 3:399-403 (2000). XP001205581
	C3	Steegen et al., "Silicide-induced stress in Si: origin and consequences for MOS technologies," <u>Materials Science and Engineering R: Reports</u> , Elsevier Sequoia S.A., Lausanne, CH. 38(1):1-53 (2002).
	C4	Yodo et al., "Influences of off-angle and off-direction of substrate on crystalline quality of GaAs and Ge heteroepitaxial films grown on vicinal Si (110) substrates by molecular-beam epitaxy", <u>Journal of Crystal Growth</u> . North-Holland Publishing Co., Amsterdam, NL. 209(4):724-733 (2000). XP004198396
	C5	International Search Report for PCT/US2004/024747 dated March 22, 2005.

EXAMINER	DATE CONSIDERED
----------	-----------------